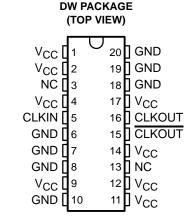
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- Generates a 622.08-MHz Clock From a 19.44-MHz TTL Clock
- Provides Differential Pseudo-ECL (PECL) Outputs
- Operates From a Single 5-V Power Supply
- Packaged in 20-Pin Plastic Small-Outline (DW) Package

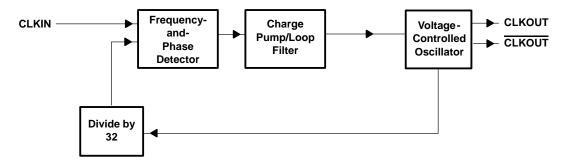
description

The TNETA1630 is a 622.08-MHz clockgeneration device that utilizes a TTL-clock input at 19.44 MHz. The 622.08-MHz clock is provided on differential pseudo-ECL (PECL) outputs. The device operates from a single 5-V power supply. An internal second-order low-pass filter is used to reduce jitter.



NC - No internal connection

functional block diagram





Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



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Terminal Functions

TERMINAL		1/0	DESCRIPTION	
NAME	NO.	1/0	DESCRIPTION	
CLKIN	5	I	19.44-MHz TTL-input clock	
CLKOUT	16	0	622.08-MHz PECL-output clock true	
CLKOUT	15	0	622.08-MHz PECL-output clock complement	
GND	6, 7, 8, 10, 18, 19, 20		Ground (0-V reference)	
VCC	1, 2, 4, 9, 11, 12, 14, 17		Supply voltage	
NC	3, 13		No connection. Leave floating.	

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note 1)		\dots -0.5 V to 7 V
Input voltage range, V _I		–1.2 V to 7 V
Operating free-air temperature range, TA	,	-40°C to 85°C
Storage temperature range, T _{stg}		-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to the GND terminals.

recommended operating conditions

			MIN	NOM	MAX	UNIT
Vсс	Supply voltage		4.75	5	5.25	V
VIH	High-level input voltage	TTL (see Note 2)	2			V
VIL	Low-level input voltage	TTL (see Note 2)			8.0	V
lıĸ	Input clamp current	TTL			-18	mA
TA	Operating free-air temperature		-40		85	°C

NOTE 2: The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic-level voltages only.

electrical characteristics over recommended ranges of operating free-air temperature and supply voltage (unless otherwise noted)

PARAMETER		TEST CONDITIONS			TYP	MAX	UNIT
VOH High-level output voltage		V _{CC} = 5 V		۷ر	CC - 0.97	' 5	V
VOL	Low-level output voltage	V _{CC} = 5 V		۷ر	CC - 1.52	25	V
VO(PP)	Output voltage swing, PECL	$V_{CC} = 4.75 \text{ V to } 5.25 \text{ V},$	See Notes 2 and 3	400			mV
VIK	Input clamp voltage	V _{CC} = 4.75 V,	I∟ = −18 mA			-1.2	V
lį	Input current, TTL	V _{CC} = 5.25 V,	$V_I = V_{CC}$ or GND			±1	μΑ
loo	Supply current	V _{CC} = 5.25 V, Outputs open	f = 622.08 MHz,			50	mA
Icc	Supply current	V _{CC} = 5.25 V, See Note 4	f = 622.08 MHz,			75	IIIA

NOTES: 2. The algebraic convention, in which the least positive (most negative) value is designated minimum, is used in this data sheet for logic-level voltages only.

- 3. PECL outputs are terminated to V_{CC} -2 V.
- 4. PECL outputs are terminated with a 50- Ω resistor to V_{CC}-2 V.



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operating characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Duty cycle, generated clock	See Note 4	45%	50%	55%	
RMS jitter, generated clock			9	12	ps
Peak-to-peak jitter, generated clock			35	120	ps

NOTE 4: PECL outputs are terminated with a 50- Ω resistor to V_{CC}-2 V.

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